

# STL13NM60N

# N-channel 600 V, 0.320 Ω, 10 A PowerFLAT™ (8x8) HV MDmesh™ II Power MOSFET

#### **Features**

Order code	V <sub>DSS</sub> @ T <sub>Jmax</sub>	R <sub>DS(on)</sub> max	I <sub>D</sub>
STL13NM60N	650 V	< 0.385 Ω	10 A <sup>(1)</sup>

- 1. The value is rated according to  $R_{\mbox{\scriptsize thj-case}}$
- 100% avalanche tested
- Low input capacitance and gate charge
- Low gate input resistance

#### **Application**

Switching applications

#### Description

This device is a N-channel Power MOSFETs made using the second generation of MDmesh™ technology. This revolutionary transistor associates a new vertical structure to the company's strip layout to yield one of the world's lowest on-resistance and gate charge. It is therefore suitable for the most demanding high efficiency converters.

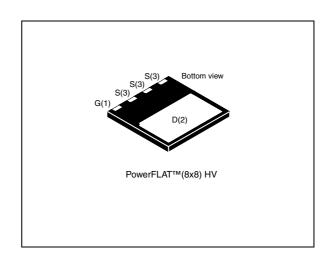


Figure 1. Internal schematic diagram

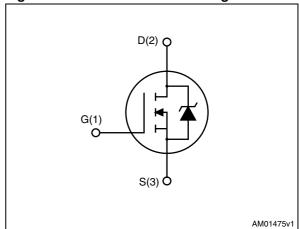


Table 1. Device summary

Order code	Marking	Package	Packaging
STL13NM60N	13NM60N	PowerFLAT™ (8x8) HV	Tape and reel

Contents STL13NM60N

# **Contents**

1	Electrical ratings
2	Electrical characteristics
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STL13NM60N Electrical ratings

# 1 Electrical ratings

Table 2. Absolute maximum ratings

Symbol	Parameter	Value	Unit
V <sub>DS</sub>	Drain-source voltage (V <sub>GS</sub> = 0)	600	V
V <sub>GS</sub>	Gate-source voltage	± 25	V
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	10	Α
I <sub>D</sub> <sup>(1)</sup>	Drain current (continuous) at T <sub>C</sub> = 100 °C	6.5	Α
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>C</sub> = 25 °C	1.9	Α
I <sub>D</sub> <sup>(2)</sup>	Drain current (continuous) at T <sub>C</sub> = 100 °C	1.1	Α
I <sub>DM</sub> <sup>(2),(3)</sup>	Drain current (pulsed)	7.6	Α
P <sub>TOT</sub> (3)	Total dissipation at T <sub>C</sub> = 25 °C (steady state)	3	W
P <sub>TOT</sub> <sup>(1)</sup>	Total dissipation at T <sub>C</sub> = 25 °C (steady state)	90	W
I <sub>AR</sub>	Avalanche current, repetitive or not- repetitive (pulse width limited by T <sub>j</sub> max)	3	А
E <sub>AS</sub>	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$ , $V_{DD} = 50$ V)	93	mJ
dv/dt (4)	Peak diode recovery voltage slope	15	V/ns
T <sub>stg</sub>	Storage temperature	- 55 to 150	°C
T <sub>j</sub>	Max. operating junction temperature	150	°C

<sup>1.</sup> The value is rated according to  $R_{\mbox{\scriptsize thj-case}}$ 

Table 3. Thermal data

Symbol	Parameter	Value	Unit
R <sub>thj-case</sub>	Thermal resistance junction-case max	1.38	°C/W
R <sub>thj-amb</sub> <sup>(1)</sup>	Thermal resistance junction-amb max	45	°C/W

<sup>1.</sup> When mounted on 1inch<sup>2</sup> FR-4 board, 2 oz Cu

<sup>2.</sup> Pulse width limited by safe operating area

<sup>3.</sup> When mounted on FR-4 board of inch²,  $2oz\ Cu$ 

<sup>4.</sup>  $I_{SD} \leq 10$  A, di/dt  $\leq 400$  A/ $\mu$ s,  $V_{DSpeak} \leq V_{(BR)DSS}$ ,  $V_{DD}$  = 80%  $V_{(BR)DSS}$ 

Electrical characteristics STL13NM60N

# 2 Electrical characteristics

 $(T_C = 25 \, ^{\circ}C \text{ unless otherwise specified})$ 

Table 4. On /off states

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V <sub>(BR)DSS</sub>	Drain-source breakdown voltage	I <sub>D</sub> = 1 mA, V <sub>GS</sub> = 0	600			٧
I <sub>DSS</sub>	Zero gate voltage drain current (V <sub>GS</sub> = 0)	$V_{DS}$ = Max rating $V_{DS}$ = Max rating, $T_{C}$ =125 °C			1 100	μ <b>Α</b> μ <b>Α</b>
I <sub>GSS</sub>	Gate-body leakage current (V <sub>DS</sub> = 0)	V <sub>GS</sub> = ± 25 V			100	nA
V <sub>GS(th)</sub>	Gate threshold voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	2	3	4	٧
R <sub>DS(on)</sub>	Static drain-source on resistance	$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		0.320	0.385	Ω

Table 5. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
C <sub>iss</sub> C <sub>oss</sub> C <sub>rss</sub>	Input capacitance Output capacitance Reverse transfer capacitance	$V_{DS} = 50 \text{ V, } f = 1 \text{ MHz,}$ $V_{GS} = 0$	-	790 60 3.6	-	pF pF pF
C <sub>oss eq.</sub> <sup>(1)</sup>	Output equivalent capacitance	V <sub>DS</sub> = 0 to 480 V, V <sub>GS</sub> = 0	-	135	-	pF
R <sub>G</sub>	Intrinsic gate resistance	f = 1 MHz open drain	-	4.7	-	Ω
Q <sub>g</sub> Q <sub>gs</sub> Q <sub>gd</sub>	Total gate charge Gate-source charge Gate-drain charge	$V_{DD} = 480 \text{ V}, I_{D} = 10 \text{ A},$ $V_{GS} = 10 \text{ V}$ (see <i>Figure 14</i> )	-	30 4 15	-	nC nC nC

C<sub>oss eq.</sub> is defined as a constant equivalent capacitance giving the same charging time as C<sub>oss</sub> when V<sub>DS</sub> increases from 0 to 80% V<sub>DS</sub>.

Table 6. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
$\begin{array}{c} t_{d(on)} \\ t_{r} \\ t_{d(off)} \\ t_{f} \end{array}$	Turn-on delay time Rise time Turn-off delay time Fall time	$V_{DD} = 300 \text{ V}, I_{D} = 10 \text{ A},$ $R_{G} = 4.7 \Omega, V_{GS} = 10 \text{ V}$ (see <i>Figure 18</i> )	-	13 25 85 50	-	ns ns ns ns

Table 7. Source drain diode

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I <sub>SD</sub>	Source-drain current Source-drain current (pulsed)		-		10 40	A A
V <sub>SD</sub> (2)	Forward on voltage	$I_{SD} = 10 \text{ A}, V_{GS} = 0$	-		1.6	V
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	I <sub>SD</sub> = 10 A, di/dt = 100 A/μs V <sub>DD</sub> = 100 V (see <i>Figure 15</i> )	-	340 2 18		ns µC A
t <sub>rr</sub> Q <sub>rr</sub> I <sub>RRM</sub>	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 10 \text{ A, di/dt} = 100 \text{ A/µs}$ $V_{DD} = 100 \text{ V, T}_{j} = 150 \text{ °C}$ (see <i>Figure 15</i> )	•	290 190 17		ns μC Α

<sup>1.</sup> Pulse width limited by safe operating area.

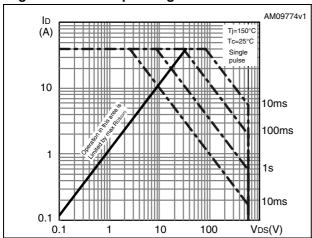
<sup>2.</sup> Pulsed: pulse duration = 300  $\mu$ s, duty cycle 1.5%

Electrical characteristics STL13NM60N

#### 2.1 Electrical characteristics (curves)

Figure 2. Safe operating area

Figure 3. Thermal impedance



Zth PowerFLAT 8x8 HV

0.2

0.1

0.05

0.02

10<sup>-1</sup>

Single pulse

10<sup>-2</sup>

10<sup>-5</sup>

10<sup>-4</sup>

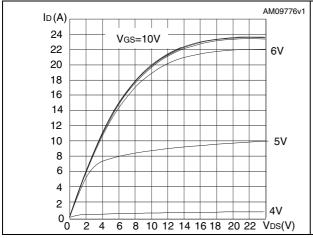
10<sup>-3</sup>

10<sup>-2</sup>

tp(S)

Figure 4. Output characteristics

Figure 5. Transfer characteristics



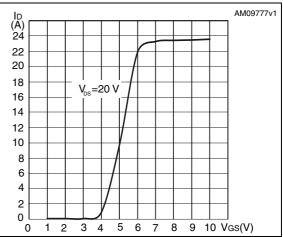
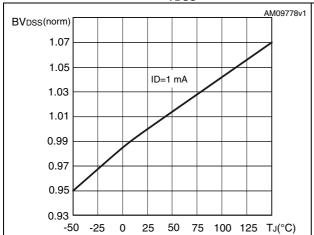
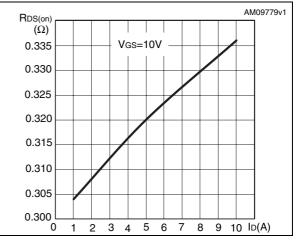


Figure 6. Normalized B<sub>VDSS</sub> vs temperature

Figure 7. Static drain-source on resistance

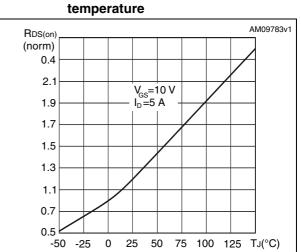




AM09780v1 AM09781v1 Vgs С (pF) (V) VDS 12 VDD=480V 500 1600 ID=11A Ciss 10 1400 400 1200 8 1000 300 6 800 Coss 200 600 4 400 100 2 200 Crss 0 V<sub>DS</sub>(V) 5 10 15 20 25 30 Qg(nC) 0.1 1 10 100

Figure 8. Gate charge vs gate-source voltage Figure 9. Capacitance variations

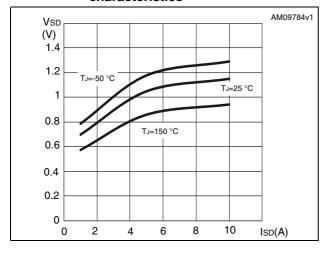
Figure 10. Normalized gate threshold voltage Figure 11. vs temperature



Normalized on resistance vs

AM09782v1 VGS(th) (norm) 1.10 I<sub>D</sub>=250 μA 1.05 1.00 0.95 0.90 0.85 0.80 0.75 0.70 -50 -25 0 25 50 75 100 125 T<sub>J</sub>(°C)

Figure 12. Source-drain diode forward characteristics



Test circuits STL13NM60N

#### 3 Test circuits

Figure 13. Switching times test circuit for resistive load

Figure 14. Gate charge test circuit

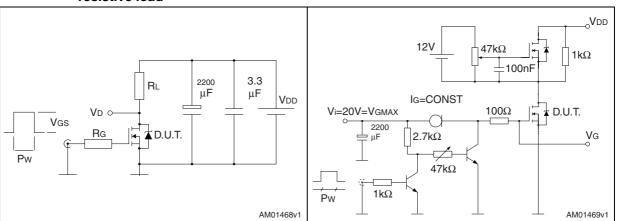


Figure 15. Test circuit for inductive load switching and diode recovery times

Figure 16. Unclamped inductive load test circuit

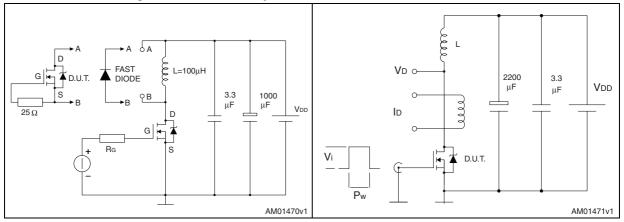
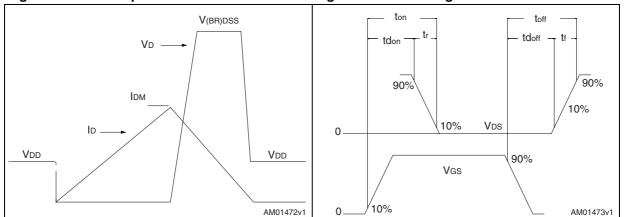


Figure 17. Unclamped inductive waveform

Figure 18. Switching time waveform



# 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: www.st.com. ECOPACK is an ST trademark.

Table 8. PowerFLAT™ 8x8 HV mechanical data

Dim.		mm	
Dilli.	Min.	Тур.	Max.
А	0.80	0.90	1.00
A1		0.02	0.05
b	0.95	1.00	1.05
С		0.10	
D		8.00	
E		8.00	
D2	7.05	7.20	7.30
E2	4.15	4.30	4.40
е		2.00	
L	0.40	0.50	0.60

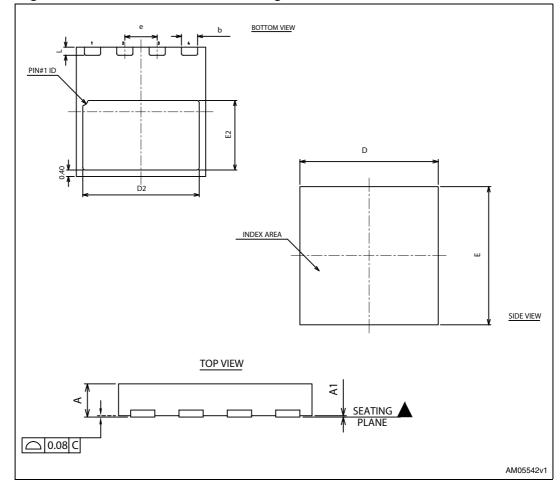


Figure 19. PowerFLAT™ 8x8 HV drawing mechanical data

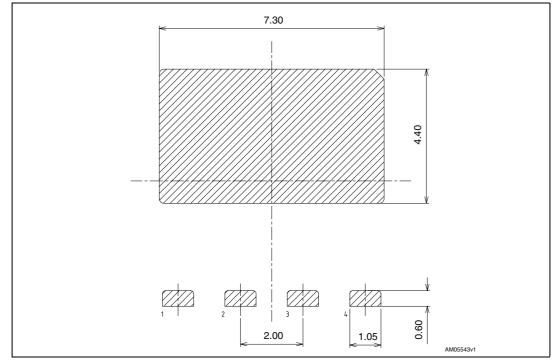


Figure 20. PowerFLAT™ 8x8 HV recommended footprint

STL13NM60N Revision history

# 5 Revision history

Table 9. Document revision history

Date	Revision	Changes
23-May-2011	1	First release.

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